Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/650,036	HAYASHI ET AL.		
Examiner	Art Unit		
Edward J. Cain	1714		

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
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